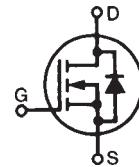


**X3-Class HiPerFET™
Power MOSFET**
IXFP60N25X3M

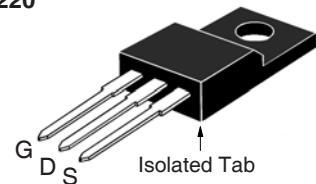
(Electrically Isolated Tab)



N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

V_{DSS} = 250V
I_{D25} = 60A
R_{DS(on)} ≤ 23mΩ

OVERMOLDED
TO-220



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	250	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	250	V
V _{GSS}	Continuous	±20	V
V _{GSM}	Transient	±30	V
I _{D25}	T _C = 25°C, Limited by T _{JM}	60	A
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	120	A
I _A	T _C = 25°C	30	A
E _{AS}	T _C = 25°C	700	mJ
dv/dt	I _S ≤ I _{DM} , V _{DD} ≤ V _{DSS} , T _J ≤ 150°C	20	V/ns
P _D	T _C = 25°C	36	W
T _J		-55 ... +150	°C
T _{JM}		150	°C
T _{stg}		-55 ... +150	°C
T _L	Maximum Lead Temperature for Soldering	300	°C
T _{SOLD}	1.6 mm (0.062in.) from Case for 10s	260	°C
M _d	Mounting Torque	1.13 / 10	Nm/lb.in
Weight		2.5	g

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	250		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 1.5mA	2.5		4.5 V
I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V			±100 nA
I _{DSS}	V _{DS} = V _{DSS} , V _{GS} = 0V T _J = 125°C			5 μA 500 μA
R _{DS(on)}	V _{GS} = 10V, I _D = 0.5 • I _{D25} , Note 1	19	23	mΩ

Features

- International Standard Package
- Plastic Overmolded Tab
- Low R_{DS(ON)} and Q_G
- Avalanche Rated
- Low Package Inductance

Advantages

- High Power Density
- Easy to Mount
- Space Savings

Applications

- Switch-Mode and Resonant-Mode Power Supplies
- DC-DC Converters
- PFC Circuits
- AC and DC Motor Drives
- Robotics and Servo Controls

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max
g_{fs}	$V_{DS} = 10\text{V}$, $I_D = 0.5 \cdot I_{D25}$, Note 1	30	50	S
R_{GI}	Gate Input Resistance		1.9	Ω
C_{iss}		3610		pF
C_{oss}		645		pF
C_{rss}		2		pF
Effective Output Capacitance				
$C_{o(er)}$	Energy related } $V_{GS} = 0\text{V}$	260		pF
$C_{o(tr)}$	Time related } $V_{DS} = 0.8 \cdot V_{DSS}$	955		pF
$t_{d(on)}$		18		ns
t_r		10		ns
$t_{d(off)}$	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 0.5 \cdot I_{D25}$	62		ns
t_f	$R_G = 5\Omega$ (External)	7		ns
$Q_{g(on)}$		50		nC
Q_{gs}	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 0.5 \cdot I_{D25}$	15		nC
Q_{gd}		17		nC
R_{thJC}			3.5	$^\circ\text{C}/\text{W}$
R_{thCS}		0.50		$^\circ\text{C}/\text{W}$

Source-Drain Diode

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max
I_s	$V_{GS} = 0\text{V}$		60	A
I_{SM}	Repetitive, Pulse Width Limited by T_{JM}		240	A
V_{SD}	$I_F = I_S$, $V_{GS} = 0\text{V}$, Note 1		1.4	V
t_{rr}		95		ns
Q_{RM}		380		nC
I_{RM}	$V_R = 100\text{V}$	8		A

Note 1. Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.

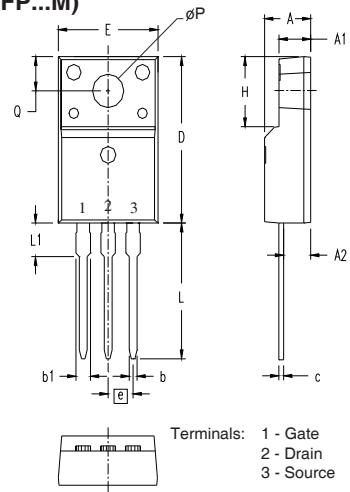
PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592, 4,931,844, 5,049,961, 5,237,481, 6,162,665, 6,404,065B1, 6,683,344, 6,727,585, 7,005,734B2, 7,157,338B2, 4,860,072, 5,017,508, 5,063,307, 5,381,025, 6,259,123B1, 6,534,343, 6,710,405B2, 6,759,692, 7,063,975B2, 4,881,106, 5,034,796, 5,187,117, 5,486,715, 6,306,728B1, 6,583,505, 6,710,463, 6,771,478B2, 7,071,537

OVERMOLDED TO-220 (IXFP...M)



SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.177	.193	4.50	4.90
A1	.092	.108	2.34	2.74
A2	.101	.117	2.56	2.96
b	.028	.035	0.70	0.90
b1	.050	.058	1.27	1.47
c	.018	.024	0.45	0.60
D	.617	.633	15.67	16.07
E	.392	.408	9.96	10.36
e	.100	BSC	2.54	BSC
H	.255	.271	6.48	6.88
L	.499	.523	12.68	13.28
L1	.119	.135	3.03	3.43
ØP	.121	.129	3.08	3.28
Q	.126	.134	3.20	3.40

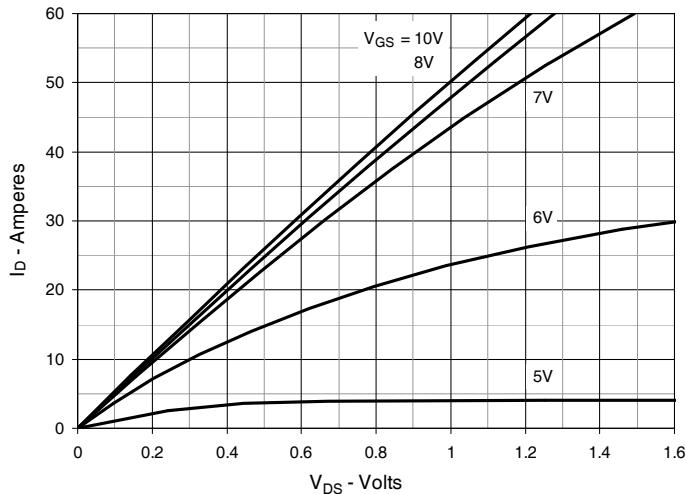
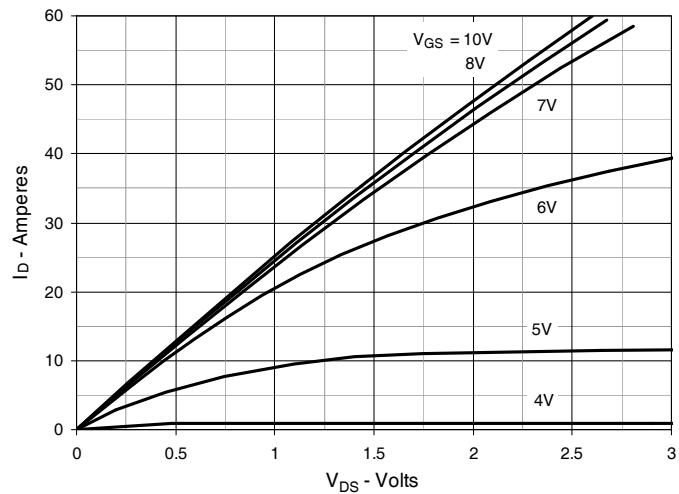
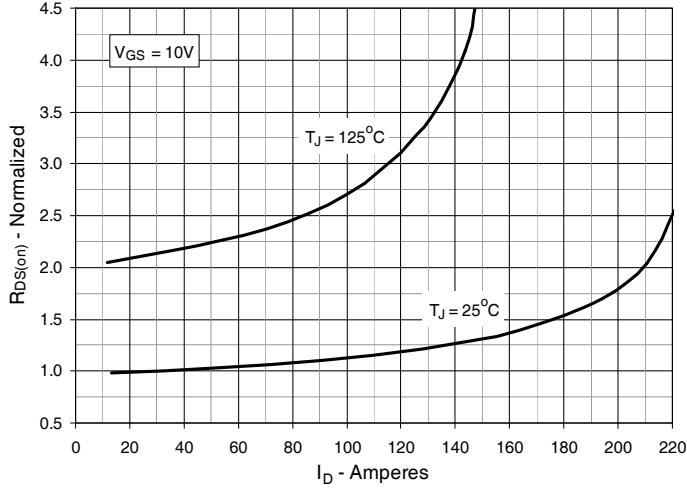
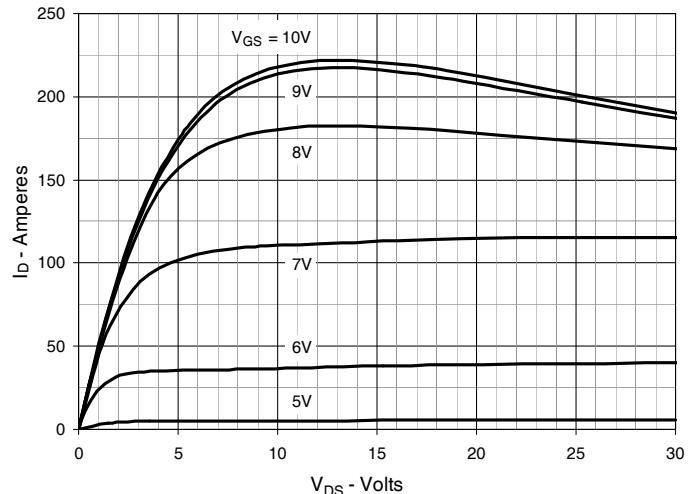
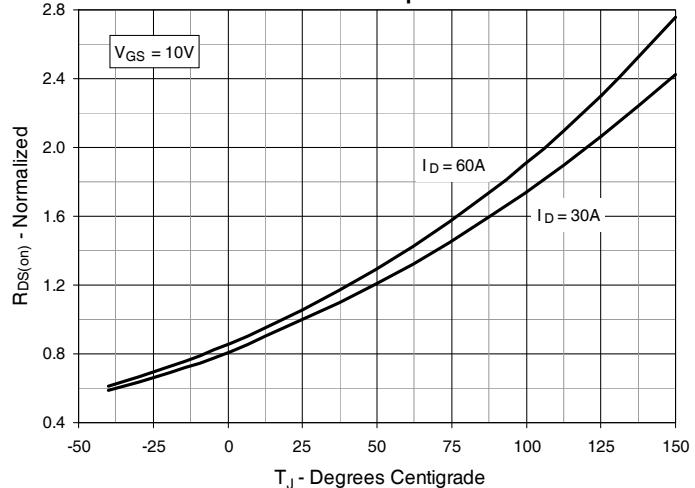
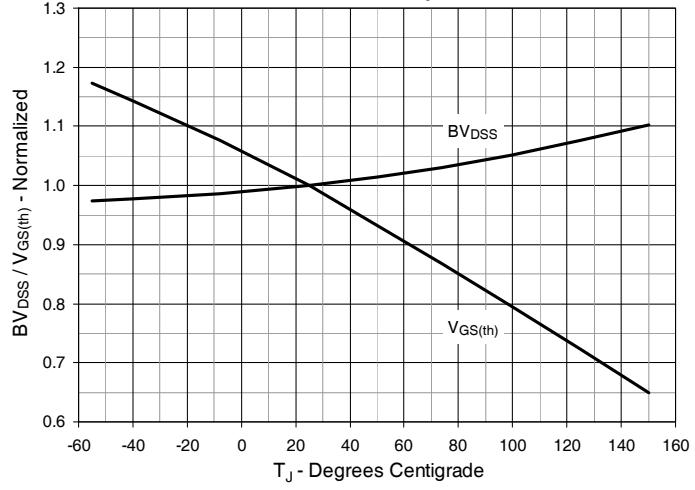
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$ **Fig. 3. Output Characteristics @ $T_J = 125^\circ\text{C}$** **Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 30\text{A}$ Value vs. Drain Current****Fig. 2. Extended Output Characteristics @ $T_J = 25^\circ\text{C}$** **Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 30\text{A}$ Value vs. Junction Temperature****Fig. 6. Normalized Breakdown & Threshold Voltages vs. Junction Temperature**

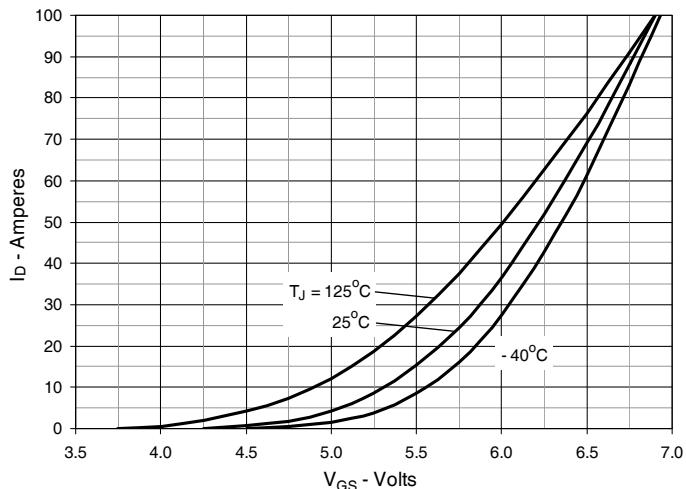
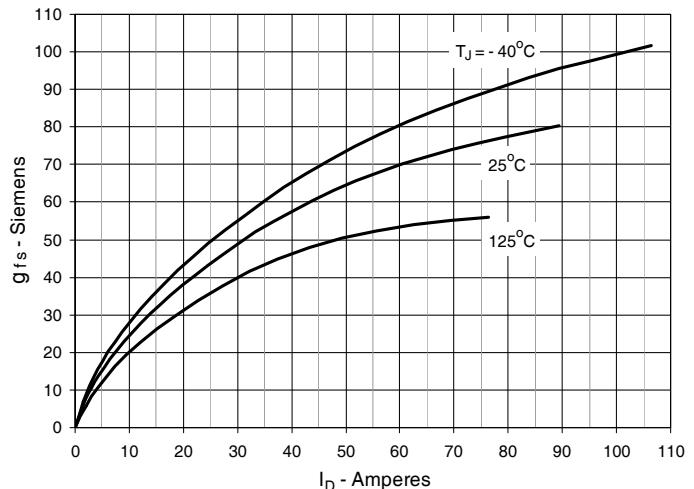
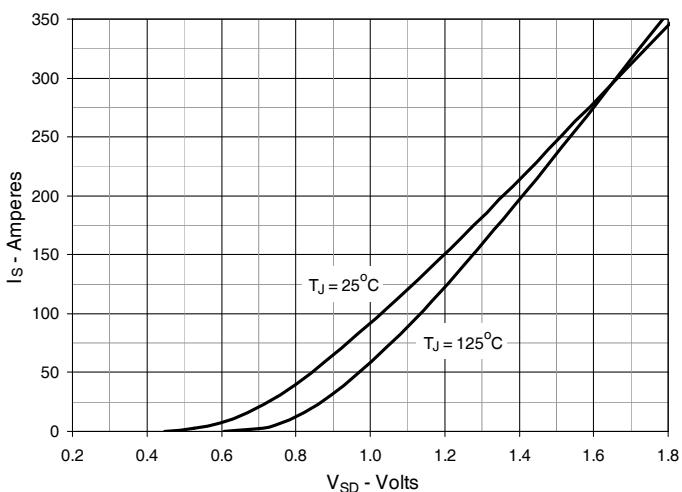
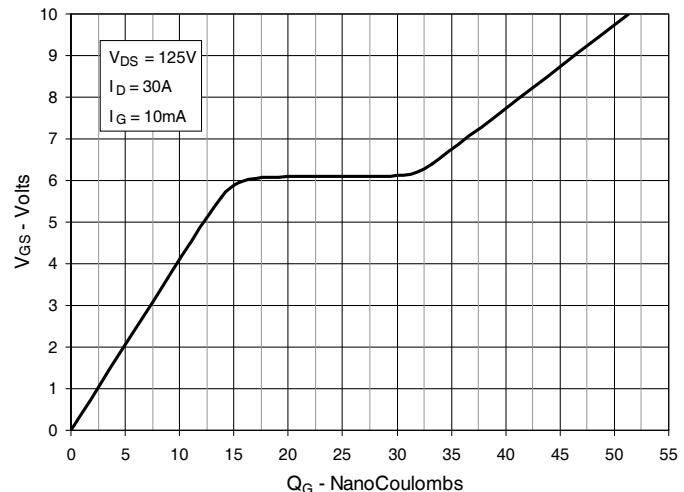
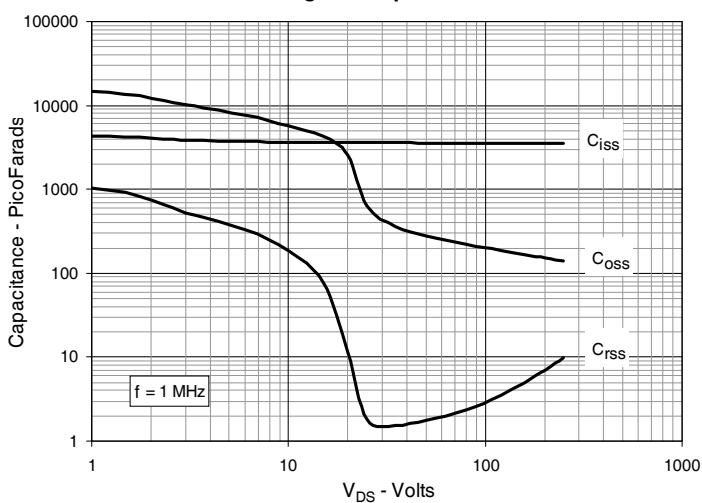
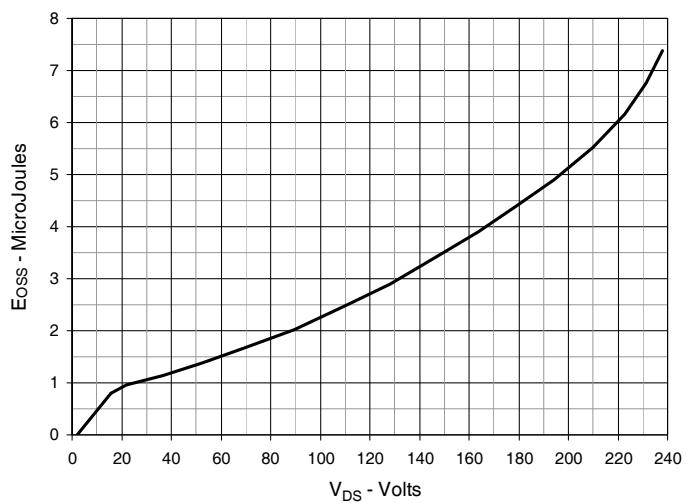
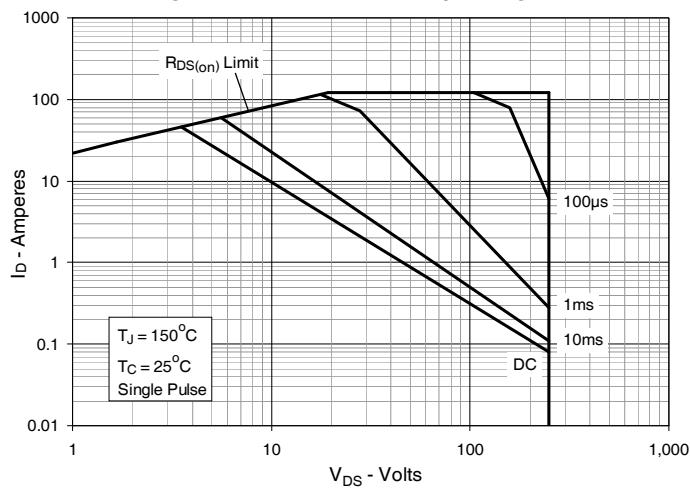
Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Forward Voltage Drop of Intrinsic Diode****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Output Capacitance Stored Energy**

Fig. 13. Forward-Bias Safe Operating Area**Fig. 14. Maximum Transient Thermal Impedance**